

Programmable high-speed decoder logic (48 × 73 × 22)

PHD48N22-7

DESCRIPTION

The PHD48N22-7 is an ultra fast Programmable High-speed Decoder featuring a 7.5ns maximum propagation delay. The architecture has been optimized using Philips Semiconductors state-of-the-art bipolar oxide isolation process coupled with titanium-tungsten fuses to achieve superior speed in any design.

The PHD48N22-7 is a two level logic element comprised of 36 fixed inputs, 73 AND gates, 10 outputs, and 12 bidirectional I/Os. This gives the device the ability to have as many as 48 inputs. Individual 3-State control of all outputs is also provided.

The device is field-programmable, enabling the user to quickly generate custom patterns using standard programming equipment. Proprietary designs can be protected by programming the security fuse.

The SLICE and SNAP software packages from Philips Components-Philips Semiconductors support easy design entry for the PHD48N22-7 as well as other PLD devices.

Order codes are listed below.

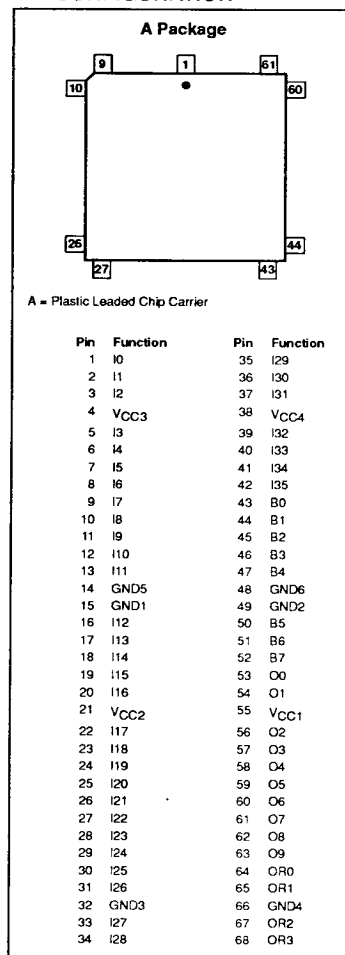
FEATURES

- Ideal for high speed system decoding
- Super high speed at 7.5ns t_{PD}
- 36 dedicated inputs
- 22 outputs
 - 12 bidirectional I/O
 - 10 dedicated outputs
- Security fuse to prevent duplication of proprietary designs.
- Individual 3-State control of all outputs
- Field-programmable on industry standard programmers
- Available in 68-Pin Plastic Leaded Chip Carrier (PLCC)

APPLICATIONS

- High speed memory decoders
- High speed code detectors
- Random logic
- Peripheral selectors
- Machine state decoders

PIN CONFIGURATION



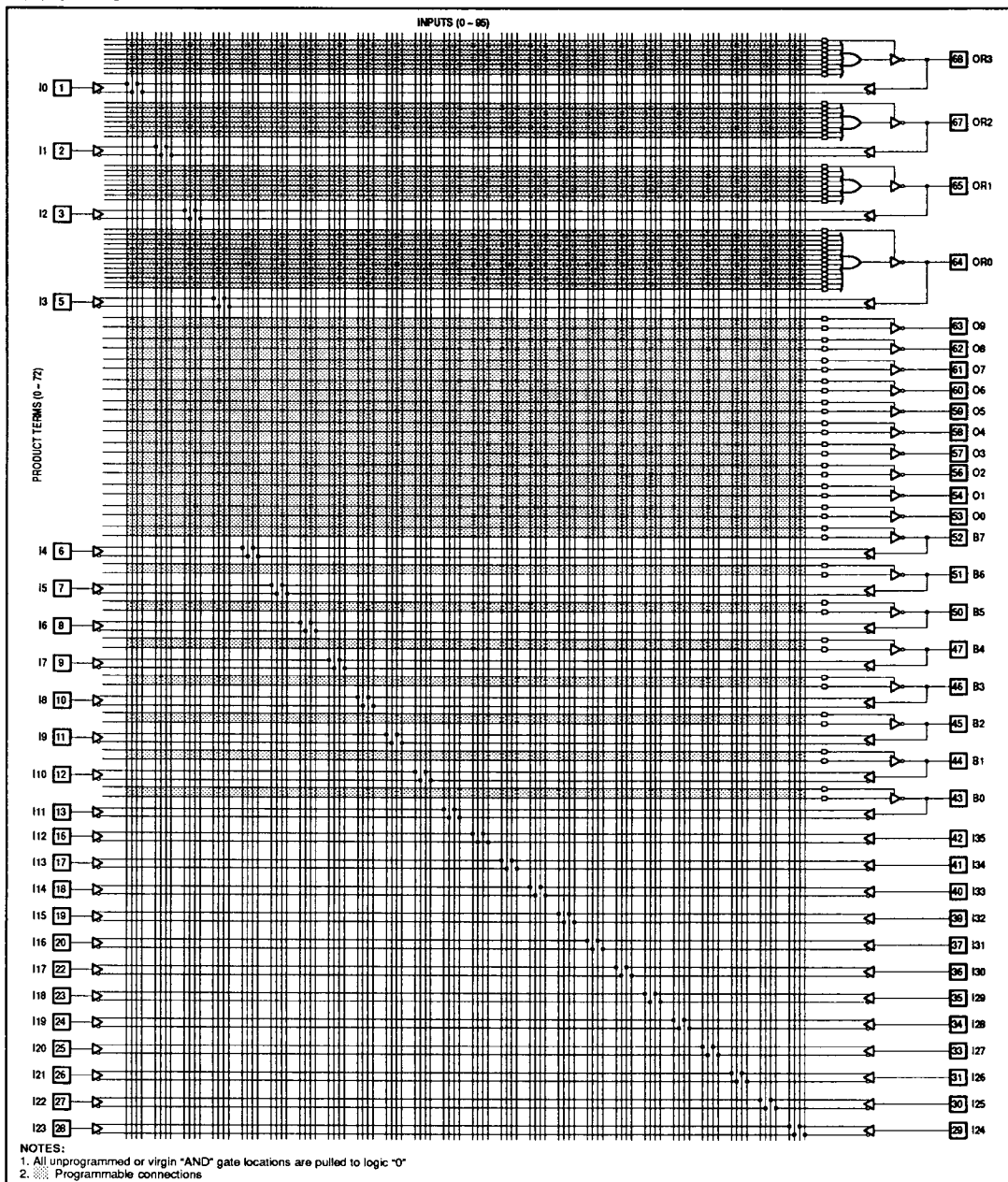
ORDERING INFORMATION

DESCRIPTION	ORDER CODE	DRAWING NUMBER
68-Pin Plastic Leaded Chip Carrier	PHD48N22-7A	0398E

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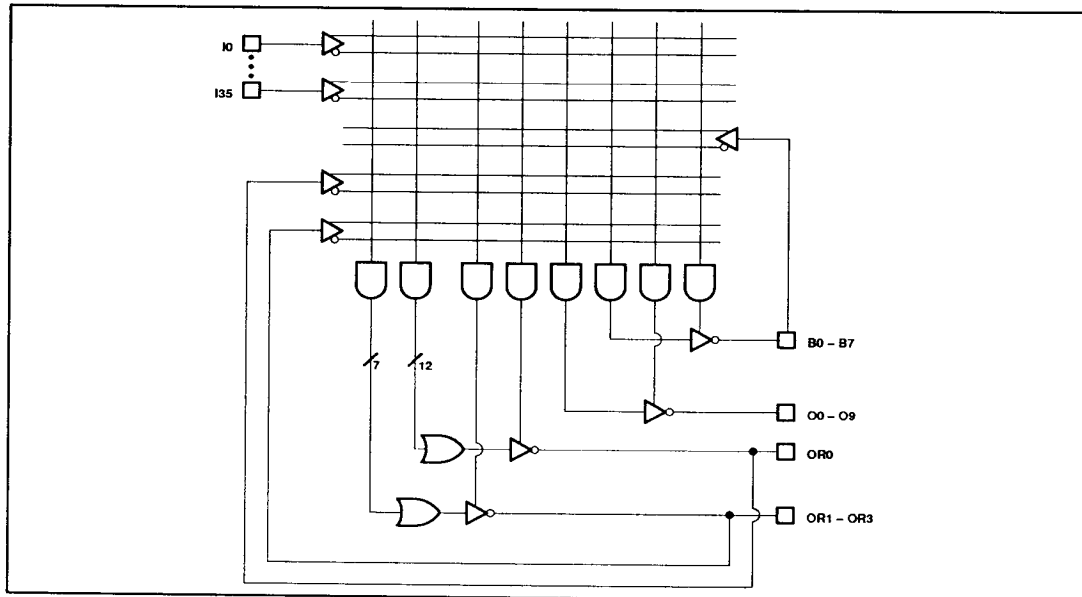
LOGIC DIAGRAM



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FUNCTIONAL DIAGRAM



ABSOLUTE MAXIMUM RATINGS¹

SYMBOL	PARAMETER	RATINGS		UNIT
		MIN	MAX	
V _{CC}	Supply voltage	-0.5	+7	V _{DC}
V _{IN}	Input voltage	-0.5	+5.5	V _{DC}
V _{OUT}	Output voltage		+5.5	V _{DC}
I _{IN}	Input currents	-30	+30	mA
I _{OUT}	Output currents		+100	mA
T _{amb}	Operating temperature range	0	+75	°C
T _{stg}	Storage temperature range	-65	+150	°C

NOTES:

- Stresses above those listed may cause malfunction or permanent damage to the device. This is a stress rating only. Functional operation at these or any other condition above those indicated in the operational and programming specification of the device is not implied.

THERMAL RATINGS

TEMPERATURE	
Maximum junction	150°C
Maximum ambient	75°C
Allowable thermal rise ambient to junction	75°C

OPERATING RANGES

SYMBOL	PARAMETER	RATINGS		UNIT
		MIN	MAX	
V _{CC}	Supply voltage	+4.75	+5.25	V _{DC}
T _{amb}	Operating free-air temperature	0	+75	°C

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DC ELECTRICAL CHARACTERISTICS

 $0^{\circ}\text{C} \leq T_{\text{amb}} \leq +75^{\circ}\text{C}$, $4.75 \leq V_{\text{CC}} \leq 5.25\text{V}$

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP ¹	MAX	
Input voltage ²						
V _{IL}	Low	V _{CC} = MIN	2.0		0.8	V
V _{IH}	High	V _{CC} = MAX			V	
V _{IC}	Clamp	V _{CC} = MIN, I _{IN} = -18mA			V	
Output voltage						
V _{OL}	Low	V _{CC} = MIN, V _{IN} = V _{IH} or V _{IL}	2.4		0.5	V
V _{OH}	High	I _{OL} = +24mA I _{OH} = -3.2mA			V	
Input current						
I _{IL}	Low	V _{CC} = MAX V _{IN} = +0.40V		-20	-250	μA
I _{IH}	High	V _{IN} = +2.7V			25	μA
I _I	High	V _{IN} = V _{CC} = V _{CC MAX}			100	μA
Output current						
I _{OZH}	Output leakage ³	V _{CC} = MAX V _{OUT} = +2.7V	-30	-60	100	μA
I _{OZL}	Output leakage ³	V _{OUT} = +0.40V			-100	μA
I _{OS}	Short circuit ⁴	V _{OUT} = +0V			-90	mA
I _{CC}	V _{CC} current	V _{CC} = MAX			420	mA
Capacitance ⁵						
C _{IN}	Input	V _{CC} = +5V V _{IN} = 2.0V @ f = 1MHz		8		pF
C _{OUT}	I/O	V _{OUT} = 2.0V @ f = 1MHz			8	pF

NOTES:

1. Typical limits are at $V_{\text{CC}} = 5.0\text{V}$ and $T_{\text{amb}} = +25^{\circ}\text{C}$.
2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.
3. Leakage current for bidirectional pins is the worst case of I_{IL} and I_{OZL} or I_{IH} and I_{OZH} .
4. Not more than one output should be tested at a time. Duration of the short circuit should not be more than one second.
5. These parameters are not 100% tested, but are periodically sampled.

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AC ELECTRICAL CHARACTERISTICS

 $0^{\circ}\text{C} \leq T_{\text{amb}} \leq +75^{\circ}\text{C}$, $4.75 \leq V_{\text{CC}} \leq 5.25\text{V}$, $R_1 = 200\Omega$, $R_2 = 390\Omega$

Operating temperature at 200 CFM Minimum air flow.

SYMBOL	PARAMETER	FROM	TO	TEST CONDITIONS	LIMITS		UNIT
					MIN	MIN	
t_{PD1}^1	Propagation delay through B/O outputs	(I, B, OR) \pm	Output \pm	$C_L = 50\text{pF}$		7.5	ns
t_{PD2}^1	Propagation delay through OR outputs	(I, B, OR) \pm	Output \pm	$C_L = 50\text{pF}$		8.0	ns
t_{OE}^2	Output Enable	(I, B, OR) \pm	Output enable	$C_L = 50\text{pF}$		10	ns
t_{OD}^2	Output Disable	(I, B, OR) \pm	Output disable	$C_L = 5\text{pF}$		10	ns

NOTES:

- $t_{PD1,2}$ are tested with switch S_1 closed and $C_L = 50\text{pF}$.
- For 3-State output; output enable times are tested with $C_L = 50\text{pF}$ to the 1.5V level, and S_1 is open for high-impedance to High tests and closed for high-impedance to Low tests. Output disable times are tested with $C_L = 5\text{pF}$. High-to-High impedance tests are made to an output voltage of $V_T = (V_{OH} - 0.5\text{V})$ with S_1 open, and Low-to-High impedance tests are made to the $V_T = (V_{OL} + 0.5\text{V})$ level with S_1 closed.

VIRGIN STATE

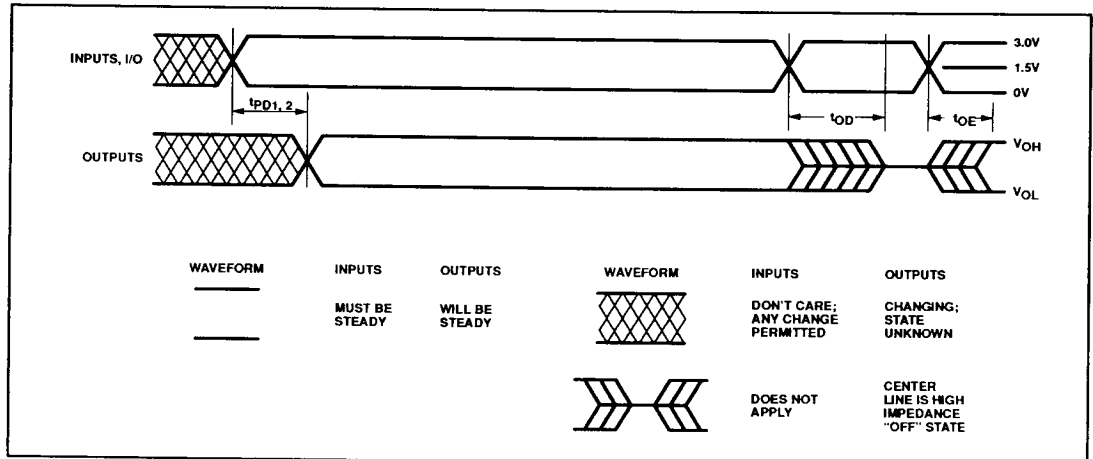
A factory shipped virgin device contains all fusible links intact, such that:

- All outputs are disabled.
- All p-terms are disabled in the AND array.

TIMING DEFINITIONS

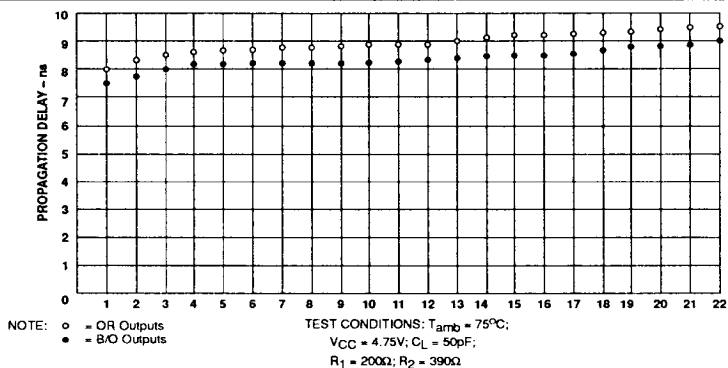
SYMBOL	PARAMETER
t_{PD1}	Input to output propagation delay (through B/O outputs).
t_{PD2}	Input to output propagation delay (through OR outputs).
t_{OD}	Input to Output Disable (3-State) delay (Output Disable).
t_{OE}	Input to Output Enable delay (Output Enable).

TIMING DIAGRAM



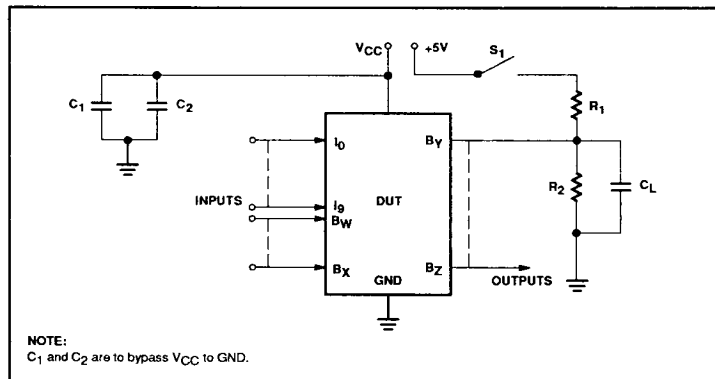
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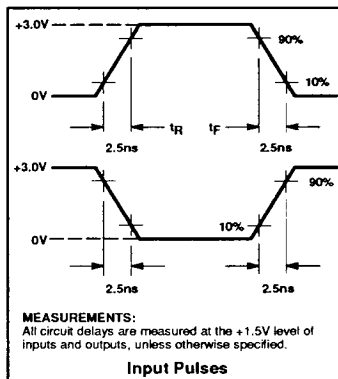


Worst-Case Propagation Delay vs. Number of Outputs Switching

AC TEST LOAD CIRCUIT



VOLTAGE WAVEFORMS



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LOGIC PROGRAMMING

The PHD48N22-7 is fully supported by industry standard (JEDEC compatible) PLD CAD tools, including Philips Semiconductors SNAP design software package. ABEL™ and CUPL™ 90 design software packages also support the architecture.

All packages allow Boolean and state equation entry formats. SNAP, ABEL and CUPL also accept, as input, schematic capture format.

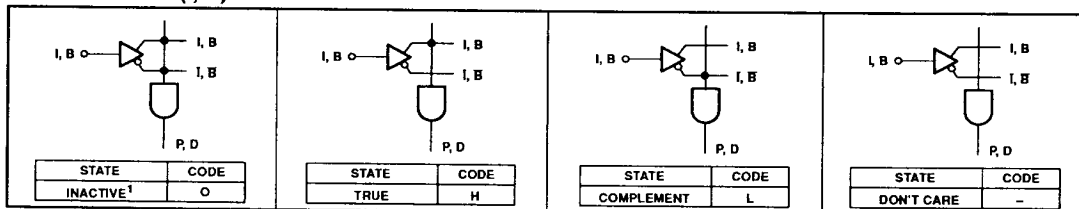
PHD48N22-7 logic designs can also be generated using the program table entry format, which is detailed on the following pages. This program table entry format is supported by SNAP only.

To implement the desired logic functions, each logic variable (I, B, P and D) from the logic equations is assigned a symbol. TRUE (High), COMPLEMENT (Low), DON'T CARE and INACTIVE symbols are defined below.

PROGRAMMING/SOFTWARE SUPPORT

Refer to Section 9 (*Development Software*) and Section 10 (*Third-Party Programmer/Software Support*) of this data handbook for additional information.

“AND” ARRAY – (I, B)



NOTE:

- This is the initial state.

ABEL is a trademark of Data I/O Corp.
CUPL is a trademark of Logical Devices, Inc.

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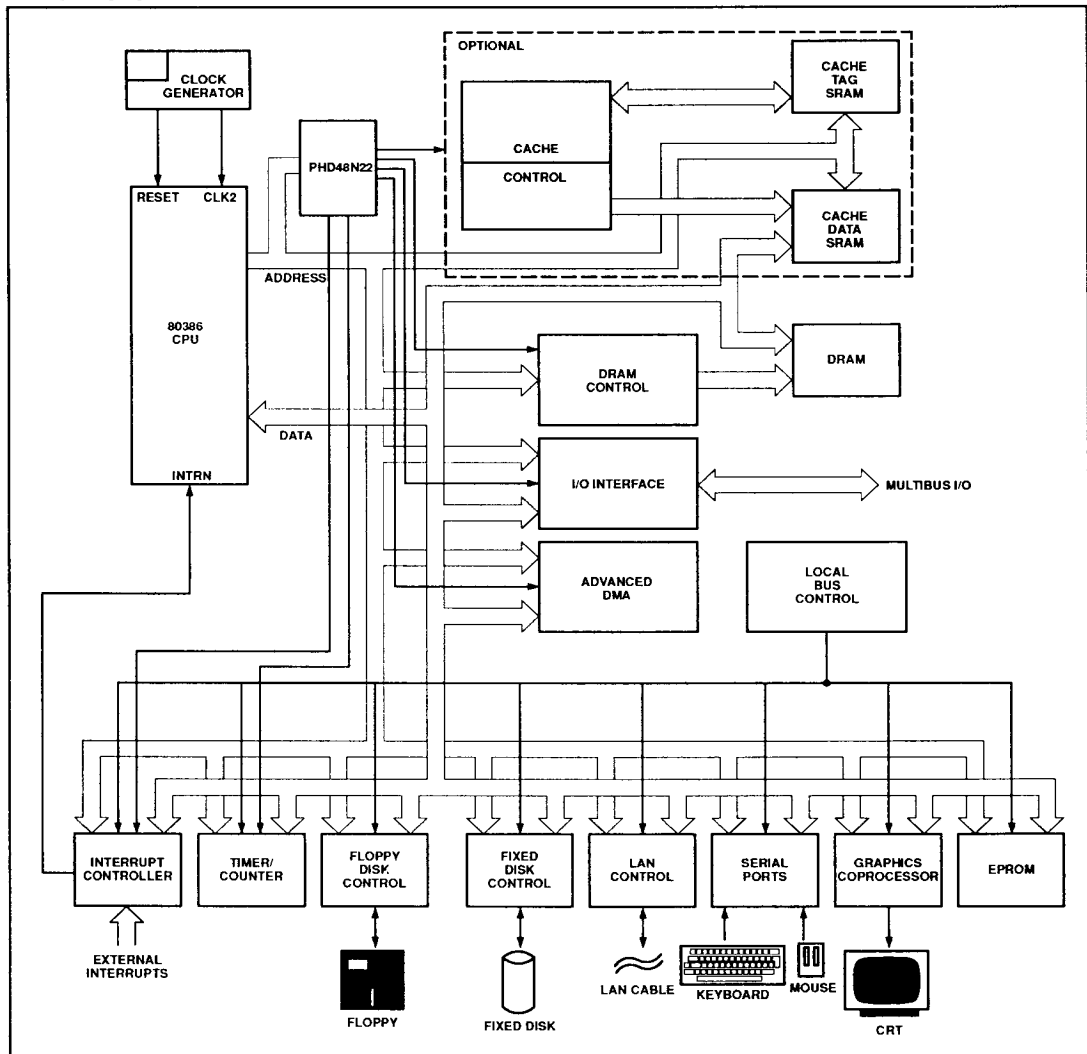
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PROGRAM TABLE (Continued)[illegible]

Programmable high-speed decoder logic ($48 \times 73 \times 22$)

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TYPICAL SYSTEM APPLICATION



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SNAP RESOURCE SUMMARY DESIGNATIONS

